

Comparison of measured reflectance spectrum and model calculation

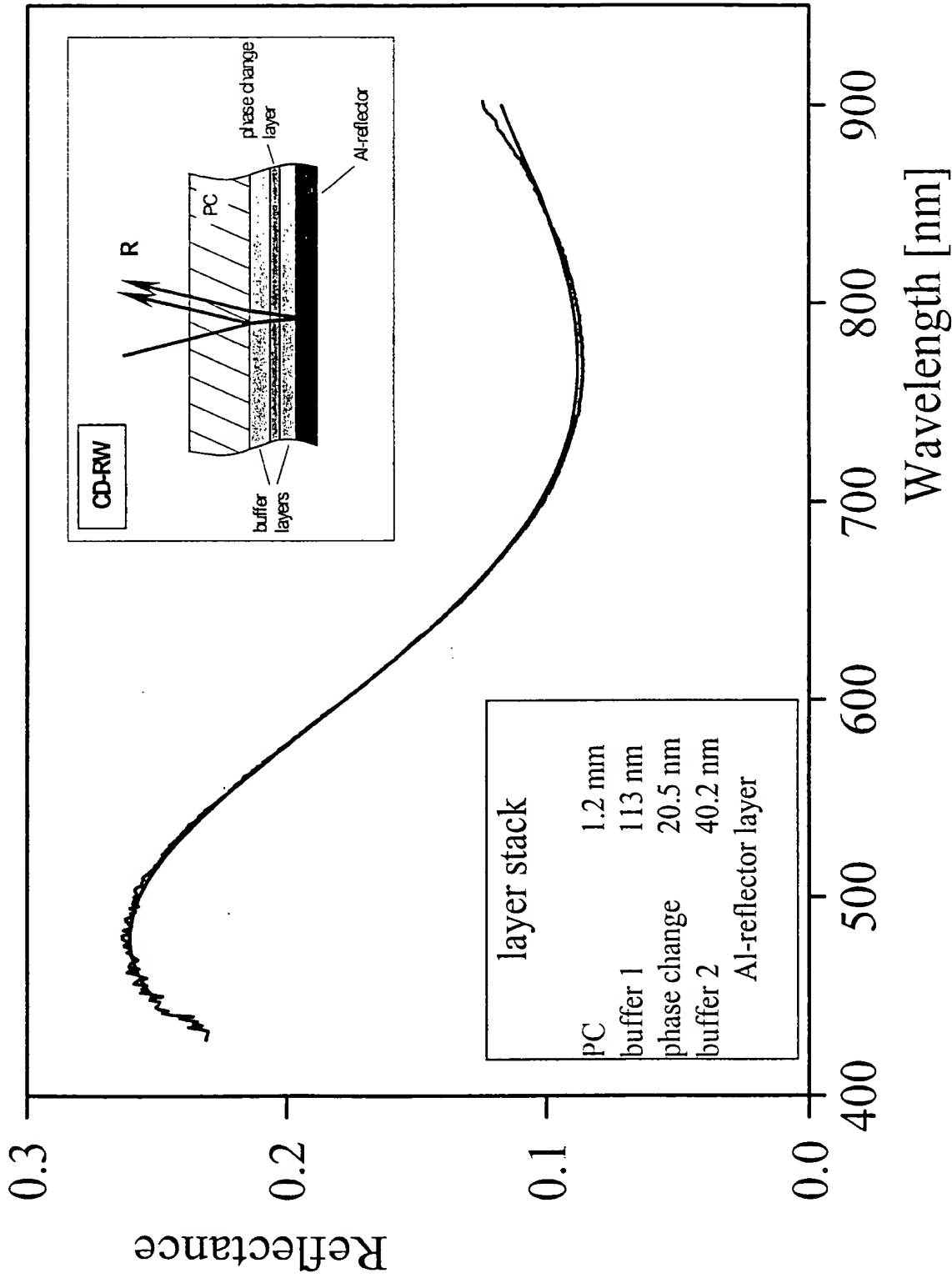


Fig.: 1

Variation of phase change layer thickness (other thickness are not varied)

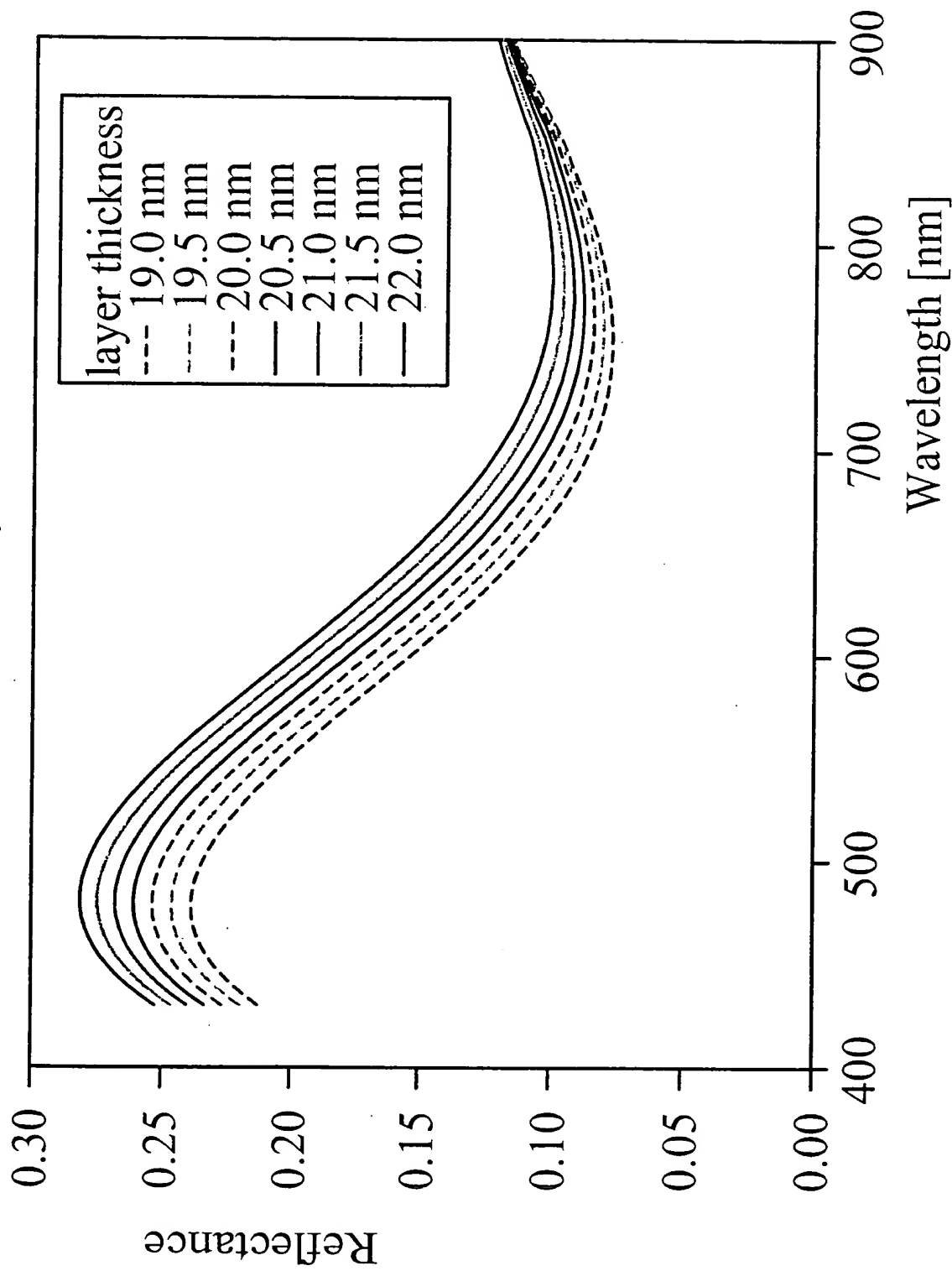


Fig.: 2

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Variation of upper buffer thickness (other thickness are not varied)

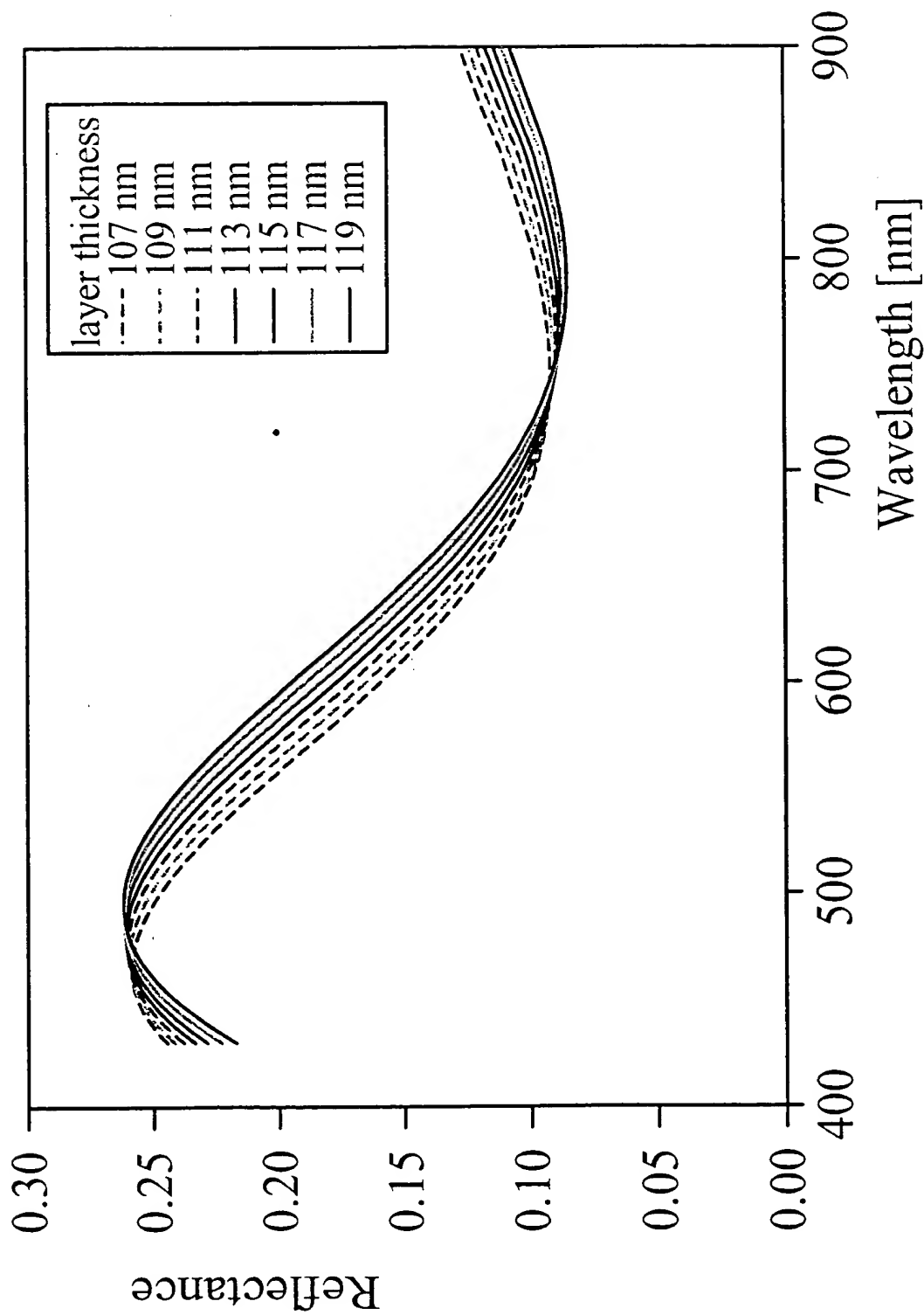


Fig.:3

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Variation of lower buffer thickness (other thickness are not varied)

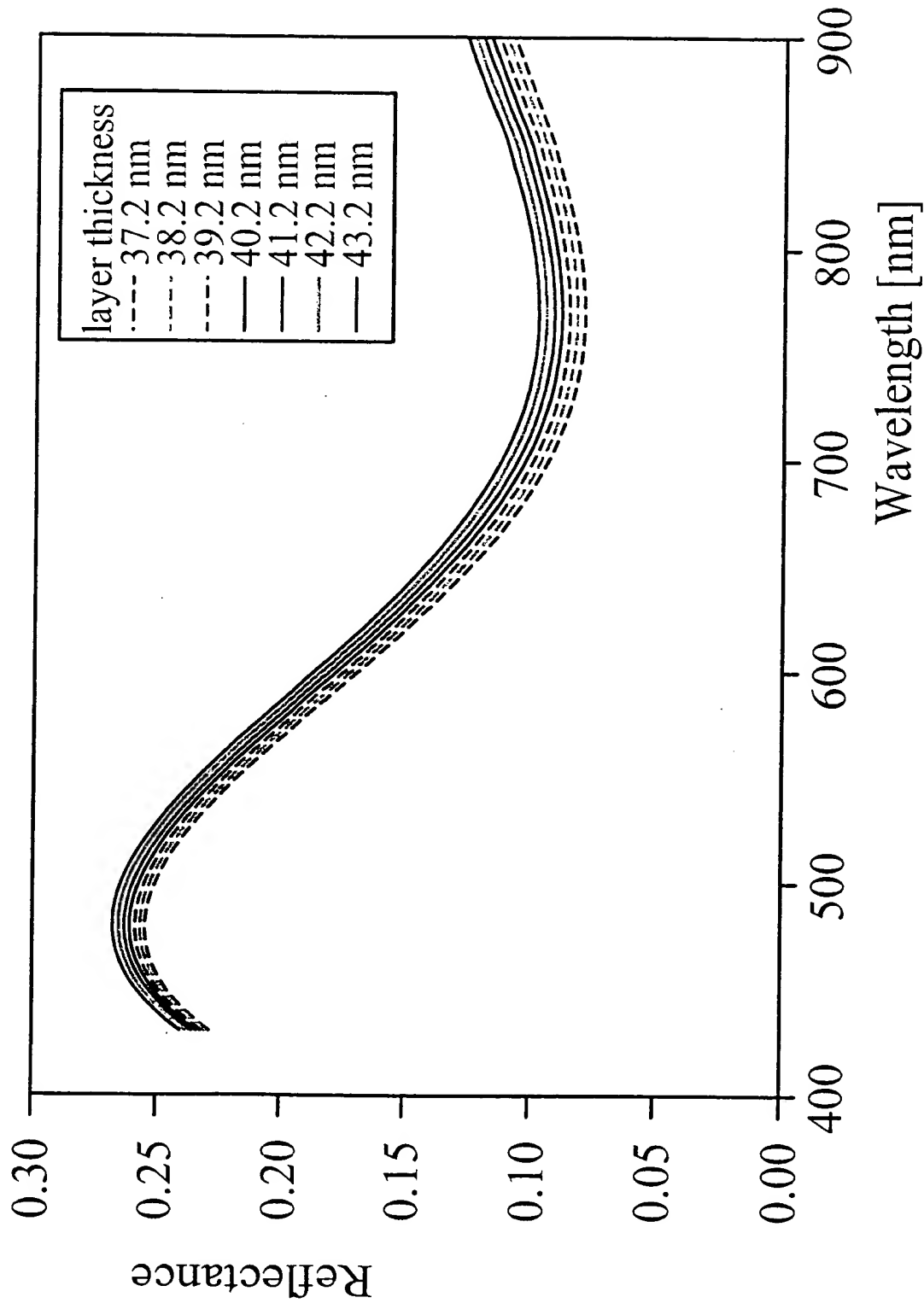


Fig.: 4

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